Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	•
10/647,762	HAN ET AL.	
Examiner	Art Unit	
Paul D. Kim	3729	

SEARCHED				
Class	Subclass	Date	Examiner	
29	592.1 603.12- 603.16 603.18 829 831	8/30/2005	PK	
	851 885			
360	121-126			
	317			
427	127 128			
451	5 41			
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

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	DATE	EXMR
Text Search EAST/NPL (IEEE)	8/31/2005	PK